

# DIN EN ISO/ASTM 52902:2020-05 (E)

## Additive manufacturing - Test artifacts - Geometric capability assessment of additive manufacturing systems (ISO/ASTM 52902:2019)

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<b>Contents</b>		<b>Page</b>
<b>European foreword</b> .....		<b>4</b>
<b>Foreword</b> .....		<b>5</b>
<b>1</b>	<b>Scope</b> .....	<b>6</b>
<b>2</b>	<b>Normative references</b> .....	<b>6</b>
<b>3</b>	<b>Terms and definitions</b> .....	<b>6</b>
<b>4</b>	<b>Significance and use</b> .....	<b>6</b>
4.1	General.....	6
4.2	Comparing results from one machine.....	7
<b>5</b>	<b>General principles for producing artifacts</b> .....	<b>7</b>
5.1	General.....	7
5.2	Need to use feedstock conforming to a material specification.....	7
5.3	Need to undertake artifact building according to a documented process specification.....	7
5.4	File formats and preparation.....	8
5.5	Download files.....	8
5.6	Discussion of file conversion.....	8
5.7	AMF preferred (with conversion instructions/ resolutions).....	8
5.8	Need for test specification and test process.....	8
5.9	Quantity of test artifacts.....	8
5.10	Position and orientation of test artifacts.....	9
5.11	Considerations for orientation.....	9
5.12	Labelling.....	9
5.13	Coverage.....	9
5.14	Arrays.....	9
5.15	Part consolidation.....	9
5.16	Supports and post processing.....	10
<b>6</b>	<b>General principles for measuring artifacts</b> .....	<b>10</b>
6.1	General.....	10
6.2	Measure parts as built.....	10
6.3	Measurement strategy.....	10
6.4	Measurement uncertainty.....	11
<b>7</b>	<b>Artifact geometries</b> .....	<b>11</b>
7.1	General.....	11
7.2	Accuracy.....	11
7.2.1	Linear artifact.....	11
7.2.2	Circular artifact.....	13
7.3	Resolution.....	15
7.3.1	Resolution pins.....	15
7.3.2	Resolution holes.....	16
7.3.3	Resolution rib.....	18
7.3.4	Resolution slot.....	20
7.4	Surface texture.....	22
7.4.1	Purpose.....	22
7.4.2	Geometry.....	22
7.4.3	Measurement.....	23
7.4.4	Reporting.....	24
7.4.5	Considerations.....	24

7.5	Labelling.....	25
7.5.1	Purpose.....	25
7.5.2	Geometry.....	25
7.5.3	Considerations.....	26
<b>Annex A</b>	<b>(informative) Example artifact configurations .....</b>	<b>27</b>
<b>Annex B</b>	<b>(informative) Measurement techniques.....</b>	<b>30</b>
<b>Annex C</b>	<b>(informative) Measurement procedures.....</b>	<b>33</b>
<b>Annex D</b>	<b>(informative) List of specimen names and sizes .....</b>	<b>39</b>
<b>Bibliography</b>	<b>.....</b>	<b>41</b>